

Time-Dependent Physics of Single-Surface Multipactor with Dual-Tone RF Carriers



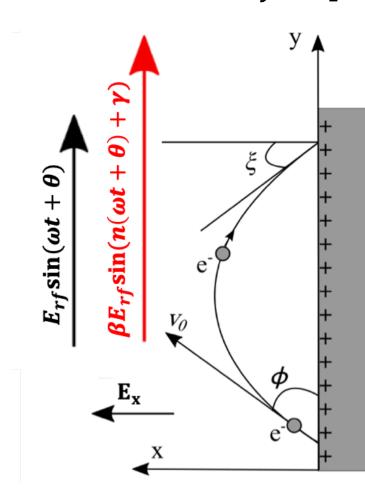
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Motivation

- Multipactor [1,2] is a nonlinear phenomenon in which an electron avalanche driven by a high frequency rf field sustains itself by an exponential charge growth through secondary electron emission from a metallic or dielectric surface.
- Multipactor causes breakdown of dielectric windows, erosion of metallic structures, melting of internal components, and perforation of vacuum walls, etc.
- Study of the time-dependent physics [3] offers a better understanding of the multipactor dynamics.

Dual tone single surface multipactor

RF Field
$$\rightarrow \vec{E}_y = \left[\vec{E}_{rf} \sin(\omega t + \theta) + \beta \vec{E}_{rf} \sin(n(\omega t + \theta) + \gamma) \right]$$



 β = relative strength of the 2nd carrier mode

- γ = relative phase of the 2nd carrier mode
- n = frequency ratio between the two carrier
- modes (need NOT be an integer)
- ϕ = initial angle of electron flight
- v_0 = initial velocity
- ξ = impact angle
- E_x = normal electric field

Monte Carlo Simulation

Distributions of random emission energy & angle [4, 5]-

$$f(E_0) = \frac{E_0}{E_{0m}^2} e^{-\left(\frac{E_0}{E_{0m}}\right)}$$
$$g(\phi) = \frac{1}{2} \sin \phi$$

 E_0 = random emission energy E_{0m} = peak of the distribution of emission energies

The Force Law

$$m\frac{\partial v}{\partial t} = -|e| \left[\vec{E}_{rf} \sin(\omega t + \theta) + \beta \vec{E}_{rf} \sin(n\omega t + \theta + \gamma) + \vec{E}_{x} \right]$$

$$\begin{cases} v_{x} = -\frac{|e|}{m} E_{x} t + v_{0} \sin\phi \\ v_{y} = \frac{|e|}{m\omega} E_{rf} \left\{ \cos(\omega t + \theta) - \cos\theta + \frac{\beta}{n} \left[\cos(n\omega t + \theta + \gamma) - \cos(\theta + \gamma) \right] \right\} \\ + v_{0} \cos\phi \end{cases}$$

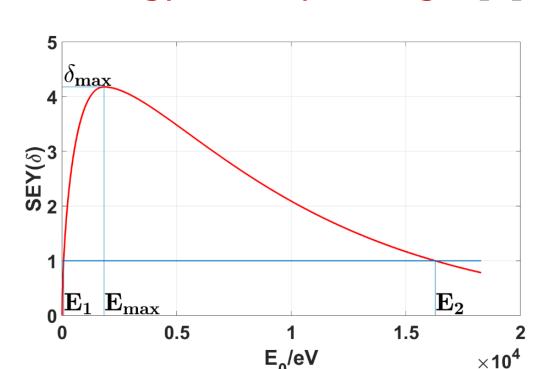
$$\begin{cases} x = -\frac{|e|}{2m} E_{x} t^{2} + v_{0} t \sin\phi + x_{0} \end{cases}$$

$$\begin{cases} y \\ = \frac{|e|}{m\omega} E_{rf} \left\{ \frac{1}{\omega} \sin(\omega t + \theta) - t \cos\theta + \frac{\beta}{n} \left[\frac{1}{n\omega} \sin(n(\omega t + \theta) + \gamma) - t \cos(n\theta + \gamma) \right] \right\} \end{cases}$$

 $+v_0tcos\phi+y_0$

Secondary Electron Yield (SEY)

Secondary electron yield (δ) depends on primary electrons' impact energy and impact angle [6].



- E₁ = first crossover point
 E₂ = second crossover point
- Impact energy between E_1 and E_2 \rightarrow $SEY > 1 \rightarrow$ charge growth
- SEY model used: Vaughan's model
 [6]

Vaughan's Model of SEY [6]

$$\delta = \delta_{max}(we^{1-w})^k, w \le 3.6$$

$$\delta = \delta_{max}(1.125/w^{0.35}), w > 3.6$$

$$k = \begin{cases} 0.56, & w < 1 \\ 0.25, & 1 \le w \le 3.6 \end{cases}$$

$$w = E_i / E_{max}$$

$$E_{max} = E_{max0} \left(1 + \frac{K_{sE} \xi^2}{2\pi} \right)$$

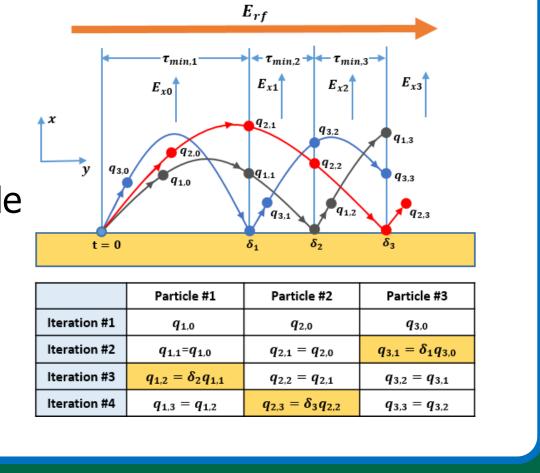
$$\delta_{max} = \delta_{max0} \left(1 + \frac{K_{s\delta} \xi^2}{2\pi} \right)$$

- $E_{max0} = \text{impact energy for } \delta_{max0}$
- $\delta_{max0} = \text{maximum yield at}$ impact angle $\xi = 0$
- $E_i = \text{impact energy of macroparticle}$
- k_{SE} , $k_{S\delta}$ = surface smoothness factors ($k_{SE} = k_{S\delta} = 1$ used)

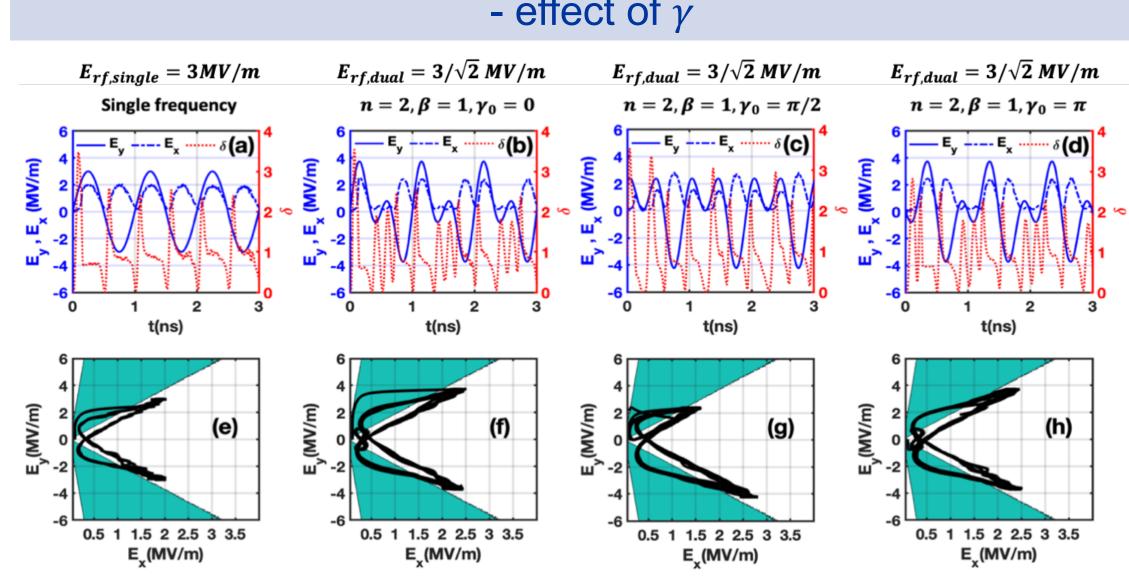
Multiparticle Monte Carlo (MC) Model

Multiparticle MC model [7]-

- large number of macroparticles
- number of macroparticles kept fixed (N = 200)
- charge in the impacting macroparticle changed and normal electric field updated at each impact
- time intervals between subsequent bounces of particles on the surface calculated exactly



Temporal study of dual tone multipactor - effect of γ



Temporal study of dual tone multipactor

- effect of γ
- Single Frequency $\rightarrow E_x$ and δ oscillates at twice the rf frequency [3]
- $n=2, \beta=1, \gamma=0, \pi \rightarrow E_x$ and δ oscillates at four times the rf frequency [7]
- $n=2, \beta=1, \gamma=\pi/2 \rightarrow E_x$ and δ oscillates at three times the rf frequency

Temporal study of dual tone multipactor

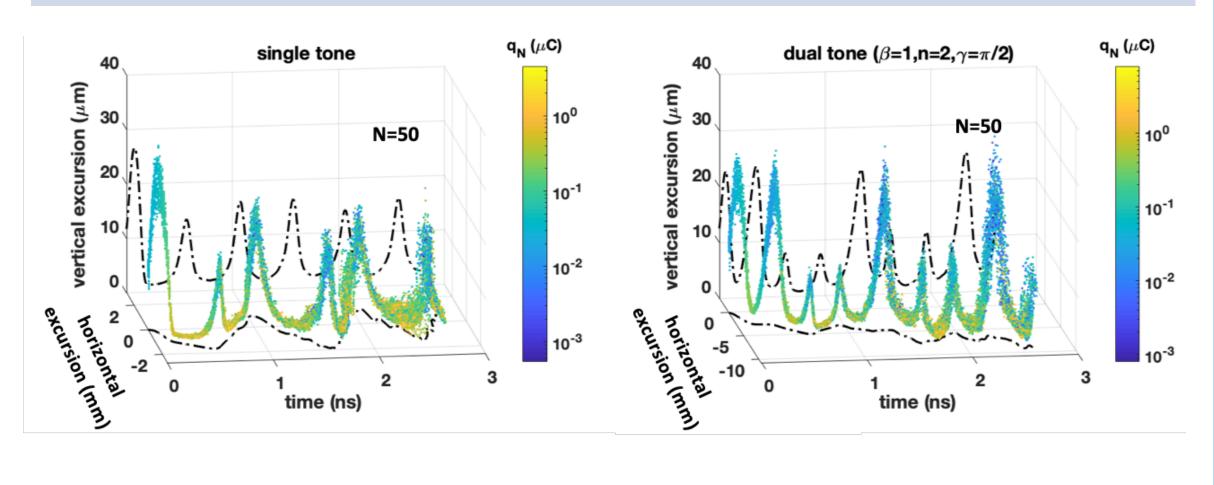
-Time spent by E_x in small and large loops

RF field configuration		Time spent (ns) in growth (decay) regime		Time averaged normal electric
		in large loops	in small loops	field $E_x(MV/m)$
Single tone		0.2 (0.8)	0 (0)	0.9
Dual tone	$n = 2, \beta = 1, \gamma_0 = 0$	0.13 (0.54)	0.17 (0.16)	0.756
	$n = 2, \beta = 1, \gamma_0 = \pi/2$	0.08 (0.25)	0.21 (0.46)	0.775
	$n=2$, $\beta=1$, $\gamma_0=\pi$	0.13 (0.54)	0.17 (0.16)	0.7501

- Dual tone operation→
 - growth time in small loops > growth time in large loops
 - growth rate in small loops < growth rate in large loops
 - lower electron population for a longer duration during an rf period [7]
 - Time averaged normal electric field E_χ (multipactor strength) reduced with the same rf power as the single tone case

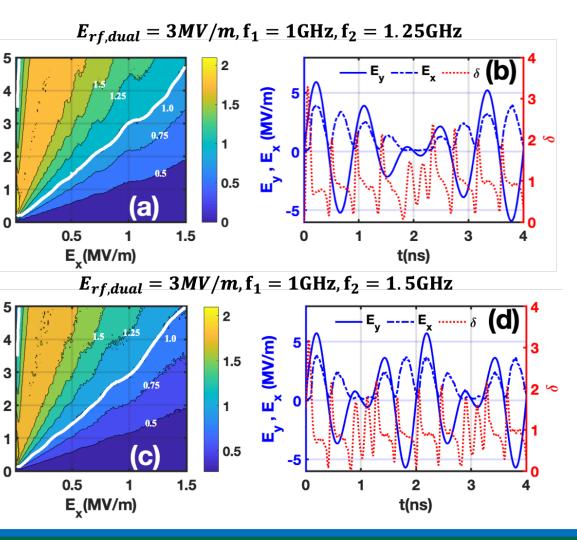
Temporal study of dual tone multipactor

- analyzing macroparticle trajectories



- Single tone operation → the rf field has periodic symmetry in positive and negative directions along the surface → negligible time averaged horizontal displacement of macroparticles
- Dual tone operation → the rf field may not have periodic symmetry in positive and negative directions along the surface → significant time averaged horizontal displacement of macroparticles
- Can be useful for cleaning a given location in a structure to reduce further susceptibility to multipactor, or for directing multipacting electrons to a specific desirable location in the geometry

Temporal study of dual tone multipactor - effect of *n*



- Susceptibility boundary relatively insensitive to the frequency ratio, n, for n=1.25, 1.5
- Temporal profile of E_{χ} significantly changes with respect to n
- Beat waves are produced in the temporal profiles of E_{χ}
- Frequency domain analysis required to resolve the frequency components of E_χ

Conclusion

- For dual tone operation of the rf electric field, the normal electric field oscillates at higher frequency than that for the single tone operation of the rf electric field.
- The time averaged normal electric field E_{χ} (corresponding to multipactor strength) is decreased compared to the single tone operation for the dual- tone case with total rf power equal to the single tone case.
- Non-integer frequency ratio between the two carrier modes produces beat wave pattern in the temporal profile of the normal electric field.
- Multipactor particle trajectories can be controlled by controlling parameters n, β , and γ of the second carrier mode.

Future Work

- Frequency domain analysis of the dual tone single surface multipactor
- Temporal study for different non-sinusoidal rf waveshapes
- Study of multi-frequency operation

Reference

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